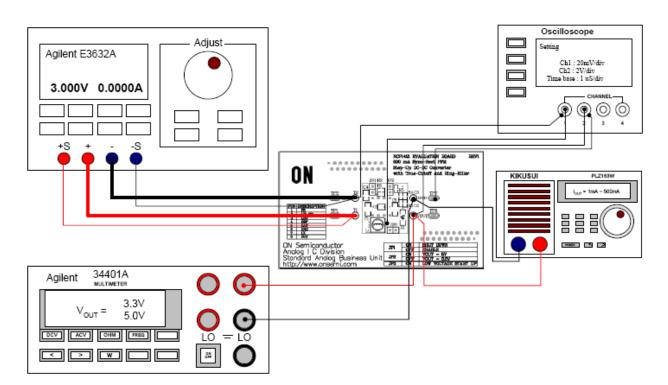


**ON Semiconductor** 



**Test Procedure for the NCP1422 Evaluation Board** 

- 1. Connect the test setup as shown above.
- 2. TURN OFF the JP; (enable the device).
- 3. Set the Power Supply to 3.0V and apply to TP1, TP2, (T1, T2).
- 4. Apply 500mA loading form the electric load.
- 5. Check the input current  $(I_{IN})$ , output voltage  $(V_{OUT})$  and output ripple;
  - For  $V_{OUT}$  = 3.3V; **JP2 OFF** I<sub>IN</sub> = 590.7mA ~ 608.7mA  $V_{OUT}$  = 3.267 ~ 3.367V  $V_{RIPPLE} \le 35mV$
  - For  $V_{OUT}$  = 5V; **JP2 ON** I<sub>IN</sub> = 931.07mA ~ 957.4mA  $V_{OUT}$  = 4.859 ~ 5.0075V  $V_{RIPPLE} \le 40mV$
- 6. Check the switching waveform at scope CH1 to see whether it is a normal continuous conduction mode switching node waveform and switching ON time  $(T_{ON})$  is between 0.46 µs ~ 1.15 µs

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